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				U.S. PATENT DOCUMENTS	3	
Examiner Initials*	Cite No.1	U.S. Patent Document			Date of Publication of	Pages, Columns, Lines, Where Relevant
		Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear
	A1	2002-0005528	A1	Masaki NAGAHARA	01/17/2002	
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FOREIGN PATENT DOCUMENTS								
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	A2	JP	09-307097	A	Sony Corp.	11/28/1997		Α
	A3	JP	2000-100831	A	NEC Corp.	04/07/2000		A
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	A5	JP	2001-189324	A	Ricoh Co. Ltd.	07/10/2001		A
	A6	JP	2002-359256	A	Fujitsu Ltd.	12/13/2002		A

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	A7	ANDO et al., "A 110-W AlGaN/GaN Heterojunction FET on Thinned Sapphire Substrate," IEDM 01, 2001, pp. 381-384.	
	A8	Li et al., "High breakdown voltage GaN HFET with field plate," Electronics Letters, February 1, 2001, Vol. 37, No. 3, pp. 196-197.	
	A9	MISHRA et al., 'AIGaN/GaN HEMTs – An Overview of Device Operation and Applications,' Proceedings of the IEEE, June 2002, vol. 90, No. 6, pp. 1022-1031.	
	A10	TAN et al., "The Effect of Dielectric Stress on the Electrical Characteristics of AlGaN/GaN Heterostructure Field-Effect Transistors (HFETs)," The 10 <sup>th</sup> IEEE International Symposium on Electron Devices for Microwave and Optelectronic Applications, November 2002, pp. 130-135.	

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